

# **CERTIFICATE OF ACCREDITATION**

## **The ANSI National Accreditation Board**

Hereby attests that

## Accurate Instrument Repair, Inc. 27122 Burbank

Foothill Ranch, CA 92610 (and satellite location as shown on the scope)

Fulfills the requirements of

## **ISO/IEC 17025:2017**

and national standard

ANSI/NCSL Z540-1-1994 (R2002)

In the field of

## CALIBRATION

This certificate is valid only when accompanied by a current scope of accreditation document. The current scope of accreditation can be verified at <u>www.anab.org</u>.



R. Douglas Leonard Jr., VP, PILR SBU

Expiry Date: 30 July 2025 Certificate Number: L2207



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).



### SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

## AND

ANSI/NCSL Z540-1-1994 (R2002)

### Accurate Instrument Repair, Inc.

27122 Burbank Foothill Ranch, CA 92610 Anthony Sargent 949-454-2874

## CALIBRATION

Valid to: July 30, 2025

Certificate Number: L2207

#### Length – Dimensional Metrology

| Parame te r/Equipme nt                               | Range                                      | Expanded Uncertainty of<br>Measurement (+/-)   | Reference Standard,<br>Method, and/or<br>Equipment                |
|--|--|--|---|
| Gaga Blocks <sup>2</sup>                             | (0.05 to 4) in                             | $(2.3 + 1.8L) \mu in$                          | Electro-mechanical  |
| Gage DIOCKS  | (5 to 20) in                               | (2+2L) µin                                     | Comparison  |
| Cylindrical Ring Gages <sup>2</sup>                  | (0.04 to 14) in                            | (4.4 + 4.1 <i>D</i> ) μin                      | Labmaster Universal   |
| Cylindrical Plug Gages <sup>2</sup><br>High Accuracy | (0.1 to 6) in                              | (5.8 + 3.8 <i>L</i> ) μin                      | Lab Master Universal,<br>Gage Blocks                              |
| Cylindrical Plug Gages <sup>2</sup><br>(Plain)       | (0.1 to 6) in                              | (28 + 3.5 <i>L</i> ) µin                       | Supermicrometer,<br>Gage Blocks                                   |
| Surface Plates <sup>1,2</sup><br>Overall Flatness    | (21 to 140) in <i>DL</i>                   | 8.5 √ <i>DL</i> μin                            | In accordance with Fed<br>Spec GGG-P-463 using<br>Leveling System |
| Local Area Flatness<br>(repeat reading)              | Up to 0.001 in                             | 33 µin   | Repeat Gage   |
| Calipers 1,2   | Up to 40 in                                | (380 + 1.8 <i>L</i> ) µin                      | Gage Blocks   |
| Indicators <sup>1,2</sup>                            | Up to 0.5 in<br>Up to 1 in<br>(1 to 12) in | 30 μin<br>290 μin<br>(320 + 0.9 <i>L</i> ) μin | Indicator Calibrator,<br>Height Master,<br>Gage Blocks            |
| Outside Micrometers <sup>1,2</sup>                   | Up to 36 in                                | $(51 + 2.3L) \mu in$                           | Gage Blocks,<br>Bing Gages  |
| Inside Micrometers <sup>1,2</sup>                    | Up to 24 in                                | (350 + 0.3L) µin                               | Plug Gages  |





#### Length – Dimensional Metrology

| Parame te r/Equipme nt                               | Range         | Expanded Uncertainty of<br>Measurement (+/-) | Reference Standard,<br>Method, and/or<br>Equipment |
|--|---------------|--|--|
| Height Gages <sup>1,2</sup>                          | Up to 40 in   | $(62 + 2.7L) \mu$ in                         | Gage Blocks,<br>Surface Plate,<br>Indicator        |
| Super Micrometers,<br>Bench Micrometers <sup>1</sup> | Up to 1 in    | 14 µin                                       | Gage Blocks  |
| Optical Comparators <sup>1</sup><br>Linearity        | Up to 16 in   | 120 µin                                      | Glass Master,<br>Magnification Scale               |
| Magnification  | Up to 12 in 🧹 | 690 µin                                      |  |

## Services performed at satellite location

26235 Enterprise Court Lake Forest, CA 92630 (all shipping, receiving and administrative functions are conducted at the main location)

#### **Electrical – DC/Low Frequency**

| Parameter/Equipment                                | Range  | Expanded Uncertainty of<br>Measurement (+/-)   | Reference Standard,<br>Method, and/or<br>Equipment |
|--|--|--|--|
| DC Current – Generate <sup>1</sup>                 | Up to 329 µA<br>330 µA to 3.29 mA<br>(3.3 to 32.9) mA<br>(33 to 329.9) mA<br>330 mA to 1.09 A<br>(1.1 to 2.9) A<br>(3 to 10.9) A<br>(11 to 20.5) A | $\begin{array}{c} 0.2 \text{ nA}/\mu\text{A} + 27 \text{ nA} \\ 0.11 \ \mu\text{A}/\text{mA} + 67 \text{ nA} \\ 0.12 \ \mu\text{A}/\text{mA} + 0.29 \ \mu\text{A} \\ 0.12 \ \mu\text{A}/\text{mA} + 2.7 \ \mu\text{A} \\ 0.23 \ \text{mA}/\text{A} + 2.7 \ \mu\text{A} \\ 0.43 \ \text{mA}/\text{A} + 91 \ \mu\text{A} \\ 0.57 \ \text{mA}/\text{A} + 0.7 \ \text{mA} \\ 1.5 \ \text{mA}/\text{A} + 1.1 \ \text{mA} \end{array}$ | Fluke Multifunction<br>Calibrator                  |
| DC Current – Generate<br>Clamp Meters <sup>1</sup> | Up to 1 000 A  | 24 µA/A + 64 µA  | Multifunction Calibrator,<br>Coil                  |
| DC Current – Measure <sup>1</sup>                  | Up to 10 mA<br>(10.1 to 100) mA<br>100.1 mA to 1 A<br>(1.1 to 3) A<br>(3.1 to 100) A   | $\begin{array}{c} 0.57 \ \mu A/mA + 2.4 \ \mu A \\ 0.57 \ \mu A/mA + 7.3 \ \mu A \\ 1.1 \ \mu A/mA + 0.14 \ mA \\ 1.4 \ mA/A + 0.7 \ mA \\ 0.047 \ \% \ of \ reading \end{array}$  | HP/Agilent Multimeter,<br>Current Shunt            |





#### **Electrical – DC/Low Frequency**

| Parameter/Equipment                                | Range  | Expanded Uncertainty of<br>Measurement (+/-)   | Reference Standard,<br>Method, and/or<br>Equipment |
|--|--|--|--|
| AC Current – Source <sup>1</sup>                   | Up to 10 kHz<br>Up to 329.9 µA<br>330 µA to 3.29 mA<br>(3.3 to 32.9) mA<br>(33 to 329.9) mA  | 9 nA/μA + 0.23 μA<br>5.8 μA/mA + 0.4 μA<br>2.3 μA/mA + 3.5 μA<br>2.3 μA/mA + 0.12 mA   | Fluke Multifunction<br>Calibrator                  |
| AC Current – Source <sup>1</sup>                   | Up to 5 kHz<br>330 mA to 2.9 A<br>(3 to 10.9) A<br>(11 to 20.5) A  | 6.9 mA/A + 1.2 mA<br>35 mA/A + 2.3 mA<br>35 mA/A + 5.3 mA  | Fluke Multifunction<br>Calibrator                  |
| AC Current – Measure <sup>1</sup>                  | Up to 3 A<br>10 Hz to 5 kHz  | 2.8 mA/A   | HP/Agilent Multimeter                              |
| Resistance – Generate <sup>1</sup><br>(Simulation) | Up to 10.9 Ω $(11 \text{ to } 32.9) \Omega$ $(33 \text{ to } 109.9) \Omega$ $(110 \text{ to } 329.9) \Omega$ $(0.33 \text{ to } 1.09) \text{ k}\Omega$ $(1.1 \text{ to } 3.29) \text{ k}\Omega$ $(1.1 \text{ to } 3.29) \text{ k}\Omega$ $(11 \text{ to } 109.9) \text{ k}\Omega$ $(11 \text{ to } 109.9) \text{ k}\Omega$ $(11 \text{ to } 109.9) \text{ k}\Omega$ $(1.1 \text{ to } 3.29) \text{ M}\Omega$ $(1.1 \text{ to } 3.29) \text{ M}\Omega$ $(1.1 \text{ to } 3.29) \text{ M}\Omega$ $(1.1 \text{ to } 32.9) \text{ M}\Omega$ $(11 \text{ to } 32.9) \text{ M}\Omega$ $(110 \text{ to } 329.9) \text{ M}\Omega$ $(110 \text{ to } 329.9) \text{ M}\Omega$ $(0.33 \text{ to } 1.1) \text{ G}\Omega$ | $ \begin{array}{c} 50 \mu\Omega/\Omega + 1.2 m\Omega \\ 36 \mu\Omega/\Omega + 1.8 m\Omega \\ 33 \mu\Omega/\Omega + 1.6 m\Omega \\ 33 \mu\Omega/\Omega + 2.3 m\Omega \\ 34 \mu\Omega/\Omega + 2.1 m\Omega \\ 34 m\Omega/k\Omega + 24 m\Omega \\ 33 m\Omega/k\Omega + 27 m\Omega \\ 34 m\Omega/k\Omega + 0.23 \Omega \\ 38 m\Omega/k\Omega + 2.2 \Omega \\ 70 \Omega/M\Omega + 37 \Omega \\ 157 \Omega/M\Omega + 52 \Omega \\ 0.31 k\Omega/M\Omega + 2.6 k\Omega \\ 0.57 k\Omega/M\Omega + 0.11 M\Omega \\ 17 k\Omega/M\Omega + 1.1 M\Omega \\ \end{array} $ | Fluke Multifunction<br>Calibrator                  |
| Resistance – Measure <sup>1</sup>                  | Up to 100 Ω<br>100.1 Ω to 1 MΩ<br>(1.1 to 10) MΩ<br>(10.1 to 100) MΩ   | $\begin{array}{c} 0.12 \ m\Omega /\Omega + 4.6 \ m\Omega \\ 0.13 \ m\Omega /\Omega + 14 \ m\Omega \\ 0.46 \ k\Omega /M\Omega + 0.11 \ k\Omega \\ 9.2 \ k\Omega /M\Omega + 12 \ k\Omega \end{array}$  | HP/Agilent Multimeter                              |
| DC Voltage – Source <sup>1</sup>                   | Up to 329 mV<br>(0.33 to 3.29) V<br>(3.3 to 32.9) V<br>(33 to 329) V<br>(330 to 1 000) V   | $\begin{array}{c} 0.2 \mu V/mV + 1.7 \mu V \\ 13.1 \mu V/V + 2.3 \mu V \\ 14 \mu V/V + 29 \mu V \\ 20.8 \mu V/V + 0.24 m V \\ 20.6 \mu V/V + 2.3 m V \end{array}$  | Fluke Multifunction<br>Calibrator                  |





#### **Electrical – DC/Low Frequency**

| Parame te r/Equipme nt   | Range  | Expanded Uncertainty of<br>Measurement (+/-)   | Reference Standard,<br>Method, and/or<br>Equipment |
|--|--|--|--|
| AC Voltage – Source <sup>1</sup>   | Up to 50 kHz<br>(1 to 32.9) mV<br>(33 to 329) mV<br>330 mV to 3.29 V<br>(3.3 to 32.9) V<br>Up to 10 kHz<br>(33 to 329.9) V<br>(330 to 1 020) V | $\begin{array}{c} 1.2 \ \mu \mbox{V/mV} + 7 \ \mu \mbox{V} \\ 0.4 \ \mu \mbox{V/mV} + 11 \ \mu \mbox{V} \\ 0.35 \ \mu \mbox{V/mV} + 59 \ \mu \mbox{V} \\ 0.4 \ m \mbox{V/V} + 1.4 \ m \mbox{V} \\ \hline 0.36 \ m \mbox{V/V} + 7.8 \ m \mbox{V} \\ 0.36 \ m \mbox{V/V} + 1.4 \ m \mbox{V} \end{array}$ | Fluke Multifunction<br>Calibrator                  |
| DC Voltage – Measure <sup>1</sup>  | Up to 100 mV<br>(0.1 to 1) V<br>(1.1 to 10) V<br>(10.1 to 100) V<br>(100.1 to 1000) V  | $55 \text{ nV/mV} + 4.5 \mu\text{V} 45 \text{ nV/mV} + 9.6 \mu\text{V} 40 \mu\text{V/V} + 69 \mu\text{V} 54 \mu\text{V/V} + 0.78 \text{ mV} 53 \mu\text{V/V} + 12 \text{ mV} $   | HP/Agilent Multimeter                              |
| AC Voltage – Measure <sup>1</sup>  | Up to 750 V<br>(3 to 5) Hz<br>(5 to 10) Hz<br>10 Hz to 20 kHz<br>(20 to 50) kHz<br>(50 to 100) kHz<br>(100 to 300) kHz                         | $12 \mu V/V + 3.5 \mu V$ $4.5 mV/V + 22 \mu V$ $1.2 mV/V + 67 \mu V$ $2 V/V + 45 \mu V$ $7.9 mV/V + 13 \mu V$ $52 mV/V + 1.9 \mu V$  | HP/Agilent Multimeter                              |
| Electrical Simulation of<br>Thermocouple Indicating<br>Devices – Source/Measure <sup>1</sup> | Type J<br>(-210 to 1 200) °C<br>Type K<br>(-100 to 1 000) °C<br>Type T<br>(-150 to 400) °C<br>Type E<br>(-100 to 1 000) °C                     | 0.31 °C<br>0.3 °C<br>0.28 °C<br>0.25 °C  | Fluke Multifunction<br>Calibrator                  |





#### Electrical – DC/Low Frequency

| Parame te r/Equipme nt            | Range                          | Expanded Uncertainty of<br>Measurement (+/-)  | Reference Standard,<br>Method, and/or<br>Equipment |
|-----------------------------------|--------------------------------|---|--|
| Capacitance – Source <sup>1</sup> |                                |   |  |
| (Simulation)                      |                                |   |  |
| 10 Hz to 3 kHz                    | (0.19 to 3.29) nF              | 5.8 p <mark>F/n</mark> F + 12 pF              |  |
| 10 Hz to 1 kHz                    | (3.3 to 10.9) nF               | 2.9 pF/nF + 12 pF                             |  |
| 10 Hz to 1 kHz                    | (11 to 109.9) nF               | 2.9 nF/nF + 0.12 nF                           |  |
| 10 Hz to 1 kHz                    | (110 to 329.9) nF              | 2.9 pF/nF + 0.34 nF                           |  |
| (10 to 600) Hz                    | (0.33 to 1.09) µF              | $2.9 \text{ nF}/\mu\text{F} + 1.2 \text{ nF}$ |  |
| (10 to 300) Hz                    | (1.1 to 3.29) µF               | $3.3 \text{ nF}/\mu\text{F} + 2.5 \text{ nF}$ | Ehilze Multifungtion                               |
| (10 to 150) Hz                    | (3.3 to 10.9) µF               | $3 nF/\mu F + 11 nF$                          | Fluke Multilunction                                |
| (10 to 120) Hz                    | (11 to 32.9) µF                | 4.7 nF/ $\mu$ F + 34 nF                       | Calibrator   |
| (10 to 80) Hz                     | (33 to 109.9) µF               | 5.3 nF/ $\mu$ F + 0.11 $\mu$ F                |  |
| (10 to 50) Hz                     | (110 to 329.9) μF              | <b>5.3</b> nF/μF + 0.34 μF                    |  |
| (10 to 20) Hz                     | (0.33 to 1.09) mF              | $5.1 \mu F/mF + 1.3 \mu F$                    |  |
| (10 to 6) Hz                      | (1.1 to <mark>3.29) m</mark> F | 5.3 μF/mF + 3.6 μF                            |  |
| (10 to 2) Hz                      | (3.3 to 10.9) mF               | $5.3 \mu F/mF + 12 \mu F$                     |  |
| (10 to 0.6) Hz                    | (11 to 32.9) mF                | 8.9 μF/mF + 36 μF                             |  |
| (10 to 0.2) Hz                    | (33 to 110) mF                 | $13 \mu F/mF + 0.12 mF$                       |  |

#### Mass and Mass Related

| Parameter/Equipment                    | Range  | Expanded Uncertainty of<br>Measurement (+/-)  | Reference Standard,<br>Method, and/or<br>Equipment |
|--|--|---|--|
| Formal                                 | Up to 100 kgf  | 0.000 012 % of reading + 22 µgf   | MIST Close E Weighte                               |
| Force                                  | Up to 500 lbf  | 0.01 % of reading + 0.012 lb  | NIST Class F weights                               |
| Torque Indicating Devices <sup>1</sup> | (0.002 to 1 000) lbf·ft  | 0.12 % of reading   | Torque Calibration System                          |
| Pressure – Source <sup>1</sup>         | (-2 to 2) psig<br>Up to 29 psig<br>Up to 50 psia<br>(35 to 1 000) psig<br>(300 to 30 000) psig | 0.006 % of reading + 0.000 09 psi<br>0.006 % of reading + 0.000 13 psi<br>0.011 % of reading + 0.000 39 psi<br>0.011 % of reading + 0.007 7 psi<br>0.023 % of reading + 0.000 1 psi | Digital Pressure Calibrators                       |
| Mass Determination                     | Up to 200 g<br>50 g to 5 kg<br>Up to 20 kg<br>Up to 50 lb                                      | 0.000 29 % of reading + 29 μg<br>0.000 26 % of reading + 1.4 mg<br>0.000 23 % of reading + 18 mg<br>0.000 2 % of reading + 0.042 lb   | ASTM E617<br>Class 1 Weights,<br>Mass Comparators  |





#### Mass and Mass Related

| Parameter/Equipment             | Range          | Expanded Uncertainty of<br>Measurement (+/-) | Reference Standard,<br>Method, and/or<br>Equipment |
|---------------------------------|----------------|--|--|
|                                 | Up to 200 g    | 0.000 3 % of reading + 39 μg                 | ASTM E617 Class 1                                  |
|                                 | (200 to 500) g | 0.000 2 % of reading + 0.83 mg               | weights and internal                               |
| Balances, Scales <sup>1,3</sup> | 500 g to 30 kg | 0.000 3 % of reading + 7.3 mg                | procedure CP-0046.1                                |
|                                 |                |  | utilized in the calibration of                     |
|                                 | Up to 90 lb    | 0.000 05 % of reading + 0.000 5 lb           | the weighing system.                               |
|                                 |                |  | ASTM E617 Class 4                                  |
|                                 |                |  | weights and internal                               |
| Balances, Scales <sup>1,3</sup> | Up to 80 kg    | 0.011 % of reading + 0.11 g                  | procedure CP-0046.1                                |
|                                 |                |  | utilized in the calibration of                     |
|                                 |                |  | the weighing system.                               |
|                                 |                |  | NIST Class F weights                               |
| Scales <sup>1,3</sup>           |                |  | and internal procedure                             |
|                                 | Up to 600 lb   | 0.011 % of reading + 0.001 5 lb              | CP-0046.1 utilized in the                          |
|                                 |                |  | calibration of the                                 |
|                                 |                |  | weighing system.                                   |

#### Thermodynamic

| Parameter/Equipment  | Range  | Expanded Uncertainty of<br>Measurement (+/-)   | Reference Standard,<br>Method, and/or<br>Equipment   |
|--|--|--|--|
| Humidity – Generate  | (10 to 95) % RH  | 0.59 % RH                                      | Two-Pressure<br>Humidity Generator   |
| Humidity – Measure <sup>1</sup>  | (10 to 95) %RH   | 1.4 %RH  | Humidity Indicator   |
|  | (-70 to 315) °C  | 0.001 % of reading + 0.095 °C                  | PRT, Sun Chamber   |
|  | 0 °C   | 0.033 °C                                       | PRT, VWR Liquid Bath   |
| Electronic based Sensors and<br>Mechanically-driven<br>Thermometers <sup>1</sup> | (-100 to 80) °C  | 0.001 % of reading + 0.029 °C                  | PRT,<br>Hart/Lauda Liquid Bath   |
|  | (35 to 280) °C   | 0.005 6 % of reading + 0.019 ° C               | PRT, Hart Liquid Bath  |
|  | (35 to 700) °C   | 0.004 9 % of reading + 0.021 ° C               | PRT, Hart Dry Well   |
| Temperature – Measure <sup>1</sup>   | (-200 to 660) °C   | 0.005 % of reading + 0.02 °C                   | PRT  |
| Infrared Thermometers <sup>1</sup>   | (50 to 100) °C<br>(100 to 200) °C<br>(200 to 300) °C<br>(300 to 400) °C<br>(400 to 500) °C | 2.4 °C<br>3.4 °C<br>4.5 °C<br>5.7 °C<br>6.5 °C | Fluke 2562 PRT Scanner<br>w/Omega RTD,<br>Hart 9132 Blackbody<br>$\mathcal{E} = 0.95, \lambda = (8 \text{ to } 14) \mu \text{m}$ |





#### **Time and Frequency**

| Parameter/Equipment               | Range            | Expanded Uncertainty of<br>Measurement (+/-) | Reference Standard,<br>Method, and/or<br>Equipment |
|-----------------------------------|------------------|--|--|
| Frequency – Generate <sup>1</sup> | 45 Hz to 2 MHz   | 5.8 mHz/Hz + 3.7 mHz                         | Fluke Multifunction<br>Calibrator                  |
| Frequency – Measure <sup>1</sup>  | 45 Hz to 300 kHz | 0 <mark>.12 H</mark> z/kHz                   | HP/Agilent Multimeter                              |

Calibration and Measurement Capability (CMC) is expressed in terms of the measurement parameter, measurement range, expanded uncertainty of measurement and reference standard, method, and/or equipment. The expanded uncertainty of measurement is expressed as the standard uncertainty of the measurement multiplied by a coverage factor of 2 (*k*=2), corresponding to a confidence level of approximately 95%.

Notes:

1. On-site calibration service is available for this parameter, since on-site conditions are typically more variable than those in the laboratory, larger measurement uncertainties are expected on-site than what is reported on the accredited scope.

2. L = length in inches, D = diameter in inches, DL = diagonal length in inches.

- 3. The CMC for Scales and Balances is highly dependent upon the resolution of the unit under test. The CMC presented here does not include the resolution of the unit under test. The resolution will be included in the reported measurement uncertainty at the time of calibration.
- 4. This scope is formatted as part of a single document including Certificate of Accreditation No. L2207.



R. Douglas Leonard Jr., VP, PILR SBU

